

**Notice of References Cited**

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Applicant(s)/Patent Under  
Reexamination

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Examiner

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Art Unit

2614

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,683,657	01-2004	Miyawaki, Mamoru	348/743
	B	US-6,219,110	04-2001	Ishikawa et al.	348/759
	C	US-6,575,579	06-2003	Ho, Leit	353/84
	D	US-6,252,636	06-2001	Bartlett, Terry A.	348/743
	E	US-2004/0051851	03-2004	Stanton et al.	353/084
	F	US-5,905,545	05-1999	Poradish et al.	348/743
	G	US-6,334,685	01-2002	Slobodin, David E.	353/31
	H	US-6,443,576	09-2002	Nishida et al.	353/98
	I	US-6,556,256	04-2003	Kato et al.	348/781
	J	US-6,619,804	09-2003	Davis et al.	353/98
	K	US-6,626,541	09-2003	Sunaga, Toshihiro	353/69
	L	US-5,192,946	03-1993	Thompson et al.	348/764
	M	US-6,246,446	06-2001	Heimbuch et al.	348/750

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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